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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0115175 A1	06-2003	Baatz et al.	707/1
	В	US-			
	O	US-			
	D	US-			
i	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	1	US-			
	J	US-		·	
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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